

Notice of References Cited	Application/Control No. 10/720,636	Applicant(s)/Patent Under Reexamination ZEIDMAN, ROBERT M.	
	Examiner J. Derek Rutten	Art Unit 2192	Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,282,698 B1	08-2001	Baker et al.	717/118
*	B	US-6,493,709 B1	12-2002	Aiken, Alexander	707/4
*	C	US-2004/0230964 A1	11-2004	Waugh et al.	717/168
*	D	US-6,978,419 B1	12-2005	Kantrowitz, Mark	715/511
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Lutz Prechelt, Guido Malpohl, and Michael Philippsen. JPlag: Finding plagiarisms among a set of programs. Technical Report 2000-1, Fakultat fur Informatik, Universitat Karlsruhe, Germany, March 2000
	V	Zeidman, R., Software Source Code Correlation, Computer and Information Science, 2006. ICIS-COMSAR 2006. 5th IEEE/ACIS International Conference on, Vol., Iss., 10-12 July 2006, Pages: 383- 392
	W	Zeidman, Bob, "Detecting Source-Code Plagiarism" June 1, 2004, Cmp Technology, Dr. Dobb's Journal, accessed and printed 3/23/07 at < http://www.ddj.com/dept/architect/184405734 >
	X	Paul Clough, Plagiarism in natural and programming languages: an overview of current tools and technologies, July 2000, Research Memoranda, CS-00-05, University of Sheffield, UK., 31 pages

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/720,636	Applicant(s)/Patent Under Reexamination ZEIDMAN, ROBERT M.	
	Examiner J. Derek Rutten	Art Unit 2192	Page 2 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Culwin et al. "Source Code Plagiarism in UK HE Computing Schools, Issues, Attitudes and Tools", September 2001, South Bank University, London, Technical Report SBU-CISM-01-01, 34 pages
	V	Joy, M.; Luck, M., Plagiarism in programming assignments, Education, IEEE Transactions on, Vol.42, Iss.2, May 1999, Pages:129-133
	W	Si, A., Leong, H. V., and Lau, R. W. 1997. CHECK: a document plagiarism detection system. In Proceedings of the 1997 ACM Symposium on Applied Computing (San Jose, California, United States). B. Bryant, J. Carroll, J. Hightower, and K. M. George, Eds. SAC '97. ACM Press, New York, NY, 70-77
	X	Johnson, M. K. 1996. Diff, Patch, and Friends. Linux J. 1996, 28es (Aug. 1996), Article 2, 9 pages

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/720,636		Applicant(s)/Patent Under Reexamination ZEIDMAN, ROBERT M.	
	Examiner J. Derek Rutten		Art Unit 2192	Page 3 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Arnow, D. 1995. ":-)When you grade that: using e-mail and the network in programming courses", In Proceedings of the 1995 ACM Symposium on Applied Computing (Nashville, Tennessee, United States, February 26 - 28, 1995). K. M. George, J. Carroll, and D. Oppenheim, Eds. SAC '95. ACM Press, New York, NY, 10-13			
	V	Worthington, "Strings", Princeton University, COS 126 Precept Notes, Archived 10/3/2000 at < http://web.archive.org/web/20001003053028/http://www.cs.princeton.edu/~lworthin/126/precepts/strings.html >			
	W	Wegmann, TLA+ Mode, Product Documentation, Archived 5/24/03 at < http://web.archive.org/web/20030524052123/http://www4.cs.uni-dortmund.de/RVS/P-TLA/TEM/doc/tla-mode_4.html >, Accessed and printed 3/26/07, 8 pages			
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.